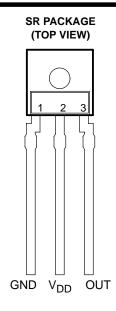
TSL253, TSL254 PRECISION HIGH-SPEED LIGHT-TO-VOLTAGE CONVERTER

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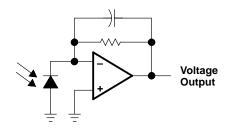
- Monolithic Silicon IC Containing Photodiode, Operational Amplifier, and Feedback Components
- Converts Light Intensity to Output Voltage
- High Irradiance Responsivity . . . Typically 60 mV/(μW/cm²) at λ_p = 880 nm (TSL253)
- High Bandwidth
- Compact 3-Leaded Clear Plastic Package
- Low Dark (Offset) Voltage . . . 10 mV Max At 25°C, V_{DD} = 5 V
- Single-Supply Operation
- Wide Supply-Voltage Range . . . 2.7 V to 5.5 V
- Low Supply Current . . . 600 μA Typical at V_{DD} = 5 V
- Advanced LinCMOS™ Technology



description

The TSL253 and TSL254 are light-to-voltage optical converters, each combining a 1-mm-square photodiode and a transimpedance amplifier (feedback resistor = $16~M\Omega$, and $1~M\Omega$ respectively) on a single monolithic IC. The output voltage is directly proportional to the light intensity (irradiance) on the photodiode. These devices utilize Texas Instruments silicon-gate LinCMOS technology, which provides improved amplifier offset-voltage stability and low power consumption.

functional block diagram



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{DD} (see Note 1)	
Output current, IO	
Duration of short-circuit current at (or below) 25°C	5 s
Operating free-air temperature range, T _A	–25°C to 85°C
Storage temperature range, T _{stg} Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	–25°C to 85°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	240°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltages are with respect to GND.



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recommended operating conditions

	MIN	MAX	UNIT
Supply voltage, V _{DD}	2.7	5.5	V
Operating free-air temperature, T _A	0	70	°C

electrical characteristics at V_{DD} = 5 V, T_A = 25°C, λp = 880 nm, R_L = 10 k Ω (unless otherwise noted) (see Notes 2 and 3)

	PARAMETER	TEST CONDITIONS	TSL253			TSL254			UNIT	
	PARAMETER		MIN	TYP	MAX	MIN	TYP	MAX	UNIT	
V_{D}	Dark voltage	$E_e = 0$			10			10	mV	
VOM	Maximum output voltage swing	$E_e = 2 \text{ mW/cm}^2$	3	3.5		3	3.5		V	
۷o	Output voltage	$E_e = 35 \mu\text{W/cm}^2$	1.6	2	2.4				V	
		$E_e = 595 \mu\text{W/cm}^2$				1.6	2	2.4		
~	Temperature coefficient of output voltage (V _O)	300 nm < λ < 700 nm		-0.2			-0.2		%/°C	
α_{VO}		$\lambda_p = 880 \text{ nm}$	0.05 0.05			70/ C				
Ne	Irradiance responsivity			60			3.5		mV/(μW/cm ²)	
	Power supply rejection, dc			60			60		dB	
	Power supply rejection, ac	f _{ac} = 1 kHz		18	·		44		dB	
I _{DD}	Supply current			0.6	1.5		0.6	1.5	mA	

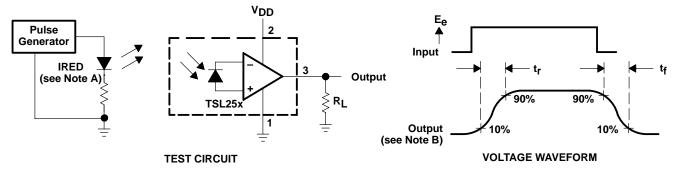
NOTES: 2. The input irradiance E_e is supplied by a GaAlAs infrared-emitting diode with λ_D = 880 nm.

3. Irradiance responsivity is characterized over the range $V_0 = 0.05$ to 3 V.

switching characteristics at $T_A = 25^{\circ}C$ (see Figure 1)

PARAMETER		TEST CONDITIONS		TSL253			TSL254			UNIT		
				MIN	TYP	MAX	MIN	TYP	MAX	ONII		
t _r	Output pulse rise time	$V_{DD} = 5 V$	$\lambda_p = 880 \text{ nm}$		7.5			2		μs		
tf	Output pulse fall time	$V_{DD} = 5 V$	$\lambda_p = 880 \text{ nm}$		7.5			2		μs		
۷ _n	Output noise voltage	V _{DD} = 5 V	f = 100 Hz		3			1.7				
			f = 1 kHz	3				1		μV/√ Hz		
			f = 10 kHz		6			1.3				

PARAMETER MEASUREMENT INFORMATION



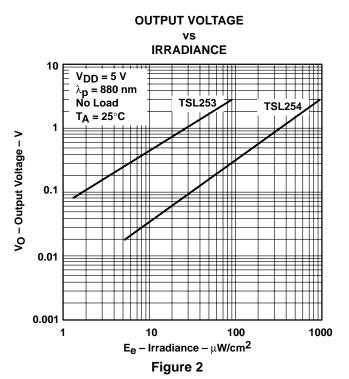
NOTES: A. The input irradiance is supplied by a pulsed GaAlAs infrared-emitting diode with the following characteristics: λ_p = 880 nm, t_r < 1 μ s, t_f < 1 μ s.

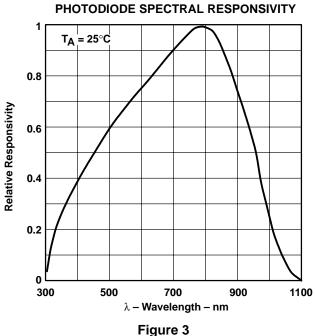
B. The output waveform is monitored on an oscilloscope with the following characteristics: t_{Γ} < 100 ns, $Z_i \ge 1$ MHz, $C_i \le 20$ pF.

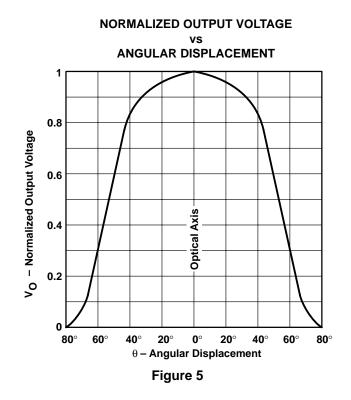
Figure 1. Switching Times



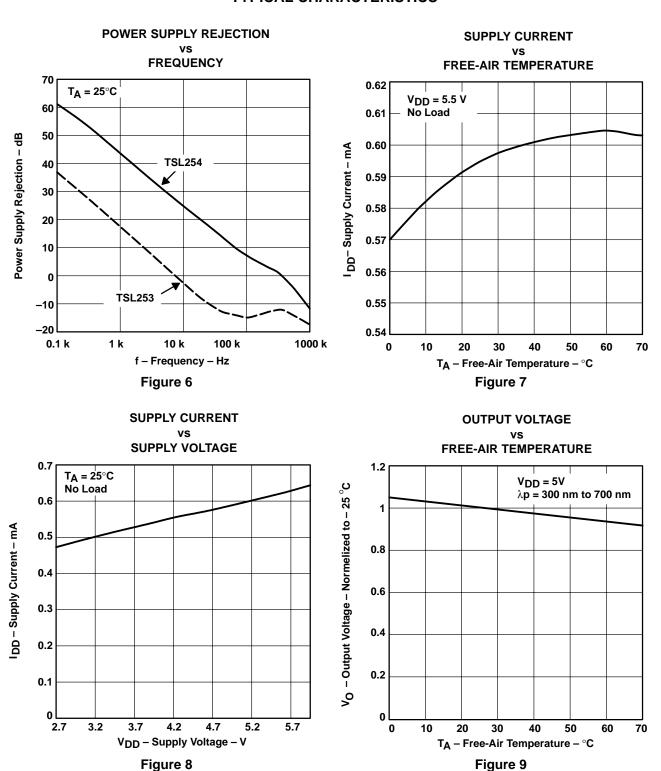
TYPICAL CHARACTERISTICS





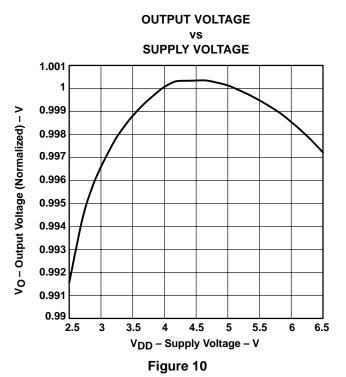


TYPICAL CHARACTERISTICS





TYPICAL CHARACTERISTICS



INTEGRATED NOISE VOLTAGE

MEASUREMENT BANDWIDTH FREQUENCY 105 $V_{DD} = 5 V$ V_{n} – Integrated Noise Voltage – μV_{rms} $T_A = 25^{\circ}C$ 104 **TSL253** 103 TSL254 102 10 1 10 100 1000 0.1 f - Measurement Bandwidth Frequency - kHz

Figure 11

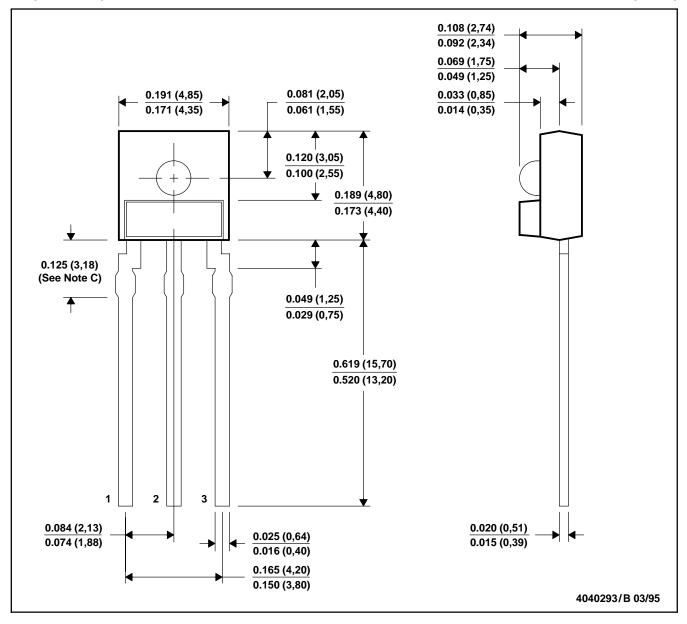


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MECHANICAL DATA

SR (R-PSIP-T3)

PLASTIC SINGLE-IN-LINE PACKAGE (OPTO)



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. Lead dimensions are not controlled within this area.
- D. All dimensions apply before solder dip.
- E. Package body is a clear nonfilled optically transparent material
- F. Index of refraction of clear plastic is 1.55.



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